SN74ALS29845 . . . DW or NT Package

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- 3-State Buffer-Type Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- Provides Extra Bus Driving Latches Necessary For Wider Address/Data Paths or Buses With Parity
- Buffered Control Inputs to Reduce DC Loading
- Power-Up High-Impedance State
- Package Options Include Plastic "Small Outline" Packages, Plastic Chip Carriers, and Standard Plastic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

description

These 8-bit latches feature three-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches are transparent D-type. The 'ALS29845 has noninverting data (D) inputs. The 'ALS29846 has inverting D inputs. Since CLR and PRE are independent of the clock, taking the CLR input low will cause the eight Q outputs to go low. Taking the PRE input low will cause the eight Q outputs to go high. When both PRE and CLR are taken low, the outputs will follow the preset condition.

The buffered output control inputs ($\overline{OC1}$, $\overline{OC2}$, and $\overline{OC3}$) can be used to place the eight outputs in either a normal logic state (high or low levels) or a high-impedance state. The outputs are also in the high-impedance state during power-up and power-down conditions. The outputs remain in the high-impedance state while the device is powered-down. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive the bus lines in a bus-organized system without need

020040DW OF NEE ackage
(Top View)
$\begin{array}{c c c c c c c c c c c c c c c c c c c $
SN74ALS29845 FN Package
(Top View)
10 003 003 003 10
2D 5 0 25 225 220 3D 6 24 320
80 CLR NC 80 80 80 80
SN74ALS29846DW or NT Package (Top View)
$\begin{array}{c c c c c c c c c c c c c c c c c c c $
SN74ALS29846 FN Package
(Top View)
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$

NC 5D	8 22	NC
5D] 9 21 [5Q
6D 7D]10 20[6Q
7D] 11 19[7Q
	8D CLR NC NC C C R R 80 80	

NC - No internal connection

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description (continued)

for interface or pullup components. The output controls do not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN74ALS29845 and SN74ALS29846 are characterized for operation from 0°C to 70°C

FUNCTION TABLES

	INPUTS									
PRE	CLR	OC 1	OC2	OC3	С	D	Q			
L	Х	L	L	L	Х	Х	Н			
н	L	L	L	L	Х	Х	L			
н	Н	L	L	L	Н	L	Н			
н	Н	L	L	L	Н	н	L			
н	Н	L	L	L	L	Х	Q ₀			
X	Х	Х	Х	Н	Х	Х	Z			
X	Х	Х	н	Х	Х	Х	Z			
Х	Х	Н	Х	Х	Х	Х	Z			

	INPUTS									
PRE	CLR	<u>0C</u> 1	OC2	OC3	С	D	Q			
L	Х	L	L	L	Х	Х	Н			
н	L	L	L	L	Х	Х	L			
н	н	L	L	L	н	L	н			
н	н	L	L	L	н	н	L			
н	н	L	L	L	L	Х	Q ₀			
Х	Х	Х	Х	н	Х	Х	Z			
X	Х	Х	н	Х	Х	Х	Z			
х	Х	Н	Х	Х	Х	Х	Z			

logic symbols[†]





[†] This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW and NT packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted) [†]
Supply voltage, V _{CC} (see Note 1)
Input voltage
Voltage applied to a disabled 3-state output 5.5 V
Operating free-air temperature range
Storage temperature range – 65°C to 150°C
[†] Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and

functional operation of the device at these or any other conditions beyond those indicated in the "Recommended Operating Conditions" section of this specification is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. NOTE 1: All voltage values in this data sheet are with respect to GND.

recommended operating conditions

			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage			5		4.75	5	5.25	V
VIH	High-level input voltage					2			V
VIL	Low-level input voltage							0.8	V
ЮН	High-level output current							- 24	mA
IOL	Low-level output current							48	mA
		PRE low	5			8			
tw	Pulse duration	CLR low	6		-	8			ns
		C high	4			6			
	Cotur time hotors anable C	Data	2.5			2.5			
t _{su}	Setup time before enable C \downarrow	PRE or CLR, inactive state	12			14			ns
t _h	Hold time, data after enable C \downarrow		4.5			4.5			ns
TA	Operating free-air temperature			25		0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST	CONDITIONS	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = 4.75 V,	lı = –18 mA			-1.2	V
	V _{CC} = 4.75 V,	I _{OH} = -15 mA	2.4	3.3		
VOH	V _{CC} = 4.75 V,	I _{OH} = – 24 mA	2	3.1		V
VOL	V _{CC} = 4.75 V,	I _{OL} = 48 mA		0.35	0.5	V
IOZH	V _{CC} = 5.25 V,	V _O = 2.7 V			20	μA
I _{OZL}	V _{CC} = 5.25 V,	$V_{O} = 0.4 V$			- 20	μA
lj	V _{CC} = 5.25 V,	V _I = 5.5 V			0.1	mA
Iн	V _{CC} = 5.25 V,	V _I = 2.7 V			20	μA
۱ _{IL}	V _{CC} = 5.25 V,	V _I = 0.4 V			- 0.2	mA
۱ _О §	V _{CC} = 5.25 V,	$V_{O} = 0$	- 75		- 250	mA
ICC	V _{CC} = 5.25 V,	Outputs low		55	85	mA

[‡] All typical values are at V_{CC} = 5 V, T_A 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		/CC = 5 \ F _A = 25°(MIN TO MIN TO		UNIT
	((001101)	oonbinono	MIN	TYP	MAX	MIN	TYP	MAX	
^t PLH			Cu = 50	2	5.7	8	2		9.5	
^t PHL			C _L = 50 pF	2	6.2	8	2		9.5	ns
tPLH	D	Any Q	C _L = 300 pF		10	12.5			14	113
^t PHL			0L = 300 bi		10	14			14	
^t PLH			<u>Cu = 50</u>		8	10.5			12	
^t PHL			С _L = 50 pF		7.5	10			12	
^t PLH	С	Any Q	Cu = 300			15			16	ns
^t PHL			C _L = 300 pF			15			16	
^t PLH	PRE	Any Q	C _L = 50 pF		6.5	9			12	ns
^t PHL	CLR	Any Q	C _L = 50 pF		7	10			13	ns
^t PZH			C 50		7.3	12			14	
^t PZL	ос	Any Q	С _L = 50 pF		9.7	12			14	ns
^t PZH		Any Q	0. 200			17			20	115
^t PZL			CL = 300 pF			21			23	
^t PHZ					10.4	14			15	
^t PLZ	ос	Any Q	C _L = 50 pF		4.7	11			12]
^t PHZ		Ally Q	C _L = 5 pF		3.4	8			9	ns
^t PLZ			0L = 3 bi		3.8	8			9	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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PARAMETER MEASUREMENT INFORMATION

SWITCH POSITION TAB	LE
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TEST	S1	S2
tplh tphl tpzh tpzl tphz tplz	Closed Closed Open Closed Closed Closed	Closed Closed Open Closed Closed

Missing illustration

NOTES: A. $\ensuremath{\mathsf{C}}_L$ includes proge and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by henerators having the following characteristics: PRR \leq 10 MHz, Z₀ = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.

Figure 1



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